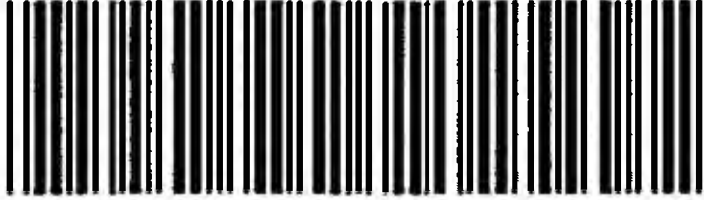


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/707,285	SLACK, KEITH E.	
	Examiner	Art Unit	
	Chi Q. Nguyen	3635	

SEARCHED			
Class	Subclass	Date	Examiner
52	749.1	9/28/2006	CN
52	749.12		
52	741.1		
52	746.11		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
BRS search	9/28/2006	CN
inventor name search	9/28/2006	CN
interference search with PG-Pub	9/28/2006	CN
search related art	9/28/2006	CN